

# REVIEW ARTICLES

S **Atomic layer deposition on polymer fibers and fabrics for multifunctional and electronic textiles**

Alexandra H. Brozena, Christopher J. Oldham and Gregory N. Parsons  
J. Vac. Sci. Technol. A **34**, 010801 (2016);  
<http://dx.doi.org/10.1116/1.4938104>

[+ VIEW DESCRIPTION](#)

TOP

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## ATOMIC LAYER DEPOSITION (ALD)

S **Thermal chemistry of copper acetamidinate atomic layer deposition precursors on silicon oxide surfaces studied by XPS**

Yunxi Yao and Francisco Zaera  
J. Vac. Sci. Technol. A **34**, 01A101 (2016);  
<http://dx.doi.org/10.1116/1.4927843>

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S **Comparison of B<sub>2</sub>O<sub>3</sub> and BN deposited by atomic layer deposition for forming ultrashallow dopant regions by solid state diffusion**

Steven Consiglio, Robert D. Clark, David O'Meara, Cory S. Wajda, Kandabara Tapily and Gert J. Leusink  
J. Vac. Sci. Technol. A **34**, 01A102 (2016);  
<http://dx.doi.org/10.1116/1.4928705>

[+ VIEW DESCRIPTION](#)

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S **Atomic layer deposition of molybdenum oxide from (N<sup>t</sup>Bu)<sub>2</sub>(NMe<sub>2</sub>)<sub>2</sub>Mo and O<sub>2</sub> plasma**

Martijn F. J. Vos, Bart Macco, Nick F. W. Thissen, Ageeth A. Bol and W. M. M. (Erwin) Kessels  
J. Vac. Sci. Technol. A **34**, 01A103 (2016);  
<http://dx.doi.org/10.1116/1.4930161>

**+ VIEW DESCRIPTION**

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S **Dynamic order reduction of thin-film deposition kinetics models: A reaction factorization approach**

Raymond A. Adomaitis  
J. Vac. Sci. Technol. A **34**, 01A104 (2016);  
<http://dx.doi.org/10.1116/1.4930591>

**+ VIEW DESCRIPTION**

---

S **Diffusion and interface evolution during the atomic layer deposition of TiO<sub>2</sub> on GaAs(100) and InAs(100) surfaces**

Liwang Ye and Theodosia Gougousi  
J. Vac. Sci. Technol. A **34**, 01A105 (2016);  
<http://dx.doi.org/10.1116/1.4931568>

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S **Vanadium dioxide film protected with an atomic-layer-deposited Al<sub>2</sub>O<sub>3</sub> thin film**

Xiao Wang, Yunzhen Cao, Chao Yang, Lu Yan and Ying Li  
J. Vac. Sci. Technol. A **34**, 01A106 (2016);  
<http://dx.doi.org/10.1116/1.4931723>

**+ VIEW DESCRIPTION**

---

S **Effect of substrate composition on atomic layer deposition using self-assembled monolayers as blocking layers**

Wenyu Zhang and James R. Engstrom  
J. Vac. Sci. Technol. A **34**, 01A107 (2016);  
<http://dx.doi.org/10.1116/1.4931722>

**+ VIEW DESCRIPTION**

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S **Mechanistic modeling study on process optimization and precursor utilization with atmospheric spatial atomic layer deposition**

Zhang Deng, Wenjie He, Chenlong Duan, Rong Chen and Bin Shan  
J. Vac. Sci. Technol. A **34**, 01A108 (2016);  
<http://dx.doi.org/10.1116/1.4932564>

**+ VIEW DESCRIPTION**

---

S **Low-temperature atomic layer deposition of copper(II) oxide thin films**

Tomi Iivonen, Jani Hämäläinen, Benoît Marchand, Kenichiro Mizohata, Miika Mattinen, Georgi Popov, Jiyeon Kim, Roland A. Fischer and Markku Leskelä  
J. Vac. Sci. Technol. A **34**, 01A109 (2016);  
<http://dx.doi.org/10.1116/1.4933089>

**+ VIEW DESCRIPTION**

---

S **Effect of hydrogen peroxide pretreatment on ZnO-based metal–semiconductor–metal ultraviolet photodetectors deposited using plasma-enhanced atomic layer deposition**

Yu-Chang Lin, Hsin-Ying Lee and Tsung-Hsin Lee  
J. Vac. Sci. Technol. A **34**, 01A110 (2016);  
<http://dx.doi.org/10.1116/1.4933169>

**+ VIEW DESCRIPTION**

---

S

## Atomic layer deposition of ultrathin Cu<sub>2</sub>O and subsequent reduction to Cu studied by *in situ* x-ray photoelectron spectroscopy

Dileep Dhakal, Khaybar Assim, Heinrich Lang, Philipp Bruener, Thomas Grehl, Colin Georgi, Thomas Waechtler, Ramona Ecke, Stefan E. Schulz and Thomas Gessner

J. Vac. Sci. Technol. A **34**, 01A111 (2016);  
<http://dx.doi.org/10.1116/1.4933088>

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---

S

## Morphology, composition and electrical properties of SnO<sub>2</sub>:Cl thin films grown by atomic layer deposition

Hsyi-En Cheng, Chia-Hui Wen and Ching-Ming Hsu

J. Vac. Sci. Technol. A **34**, 01A112 (2016);  
<http://dx.doi.org/10.1116/1.4933328>

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---

S

## Blistering during the atomic layer deposition of iridium

Pascal Genevée, Ernest Ahiavi, Norik Janunts, Thomas Pertsch, Maria Oliva, Ernst-Bernhard Kley and Adriana Szeghalmi

J. Vac. Sci. Technol. A **34**, 01A113 (2016);  
<http://dx.doi.org/10.1116/1.4934753>

[+ VIEW DESCRIPTION](#)

---

S

## Gas permeation barriers deposited by atmospheric pressure plasma enhanced atomic layer deposition

Lukas Hoffmann, Detlef Theirich, Tim Hasselmann, André Räupe, Daniel Schlamm and Thomas Riedl

J. Vac. Sci. Technol. A **34**, 01A114 (2016);  
<http://dx.doi.org/10.1116/1.4935337>

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---

S **Atomic layer deposited cobalt oxide: An efficient catalyst for NaBH<sub>4</sub> hydrolysis**

Dip K. Nandi, Joydev Manna, Arpan Dhara, Pratibha Sharma and Shaibal K. Sarkar

J. Vac. Sci. Technol. A **34**, 01A115 (2016);

<http://dx.doi.org/10.1116/1.4935353>

**+ VIEW DESCRIPTION**

---

S **Novel copper compounds for vapor deposition: Characterization and thermolysis**

Agnes Kurek, Glenn P. A. Yap and Seán T. Barry

J. Vac. Sci. Technol. A **34**, 01A116 (2016);

<http://dx.doi.org/10.1116/1.4935447>

**+ VIEW DESCRIPTION**

---

S **Spectroscopic investigation of the electronic structure of thin atomic layer deposition HfO<sub>2</sub> films**

Silma Alberton Corrêa, Simone Brizzi and Dieter Schmeisser

J. Vac. Sci. Technol. A **34**, 01A117 (2016);

<http://dx.doi.org/10.1116/1.4935338>

**+ VIEW DESCRIPTION**

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S **Room temperature plasma enhanced atomic layer deposition for TiO<sub>2</sub> and WO<sub>3</sub> films**

Alexander Strobel, Hans-Dieter Schnabel, Ullrich Reinhold, Sebastian Rauer and Andreas Neidhardt

J. Vac. Sci. Technol. A **34**, 01A118 (2016);

<http://dx.doi.org/10.1116/1.4935356>

**+ VIEW DESCRIPTION**

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S

## **Atomic layer deposition of environmentally benign SnTiO<sub>x</sub> as a potential ferroelectric material**

Siliang Chang, Sathees Kannan Selvaraj, Yoon-Young Choi, Seungbum Hong, Serge M. Nakhmanson and Christos G. Takoudis

J. Vac. Sci. Technol. A **34**, 01A119 (2016);

<http://dx.doi.org/10.1116/1.4935650>

**+ VIEW DESCRIPTION**

---

S

## **Ultraviolet optical properties of aluminum fluoride thin films deposited by atomic layer deposition**

John Hennessy, April D. Jewell, Kunjithapatham Balasubramanian and Shouleh Nikzad

J. Vac. Sci. Technol. A **34**, 01A120 (2016);

<http://dx.doi.org/10.1116/1.4935450>

**+ VIEW DESCRIPTION**

---

S

## **Fast spatial atomic layer deposition of Al<sub>2</sub>O<sub>3</sub> at low temperature (<100 °C) as a gas permeation barrier for flexible organic light-emitting diode displays**

Hagyoung Choi, Seokyeon Shin, Hyeongtag Jeon, Yeongtae Choi, Junhun Kim, Sanghun Kim, Seog Chul Chung and Kiyong Oh

J. Vac. Sci. Technol. A **34**, 01A121 (2016);

<http://dx.doi.org/10.1116/1.4934752>

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S

## **Experimental demonstration of single electron transistors featuring SiO<sub>2</sub> plasma-enhanced atomic layer deposition in Ni-SiO<sub>2</sub>-Ni tunnel junctions**

Golnaz Karbasian, Michael S. McConnell, Alexei O. Orlov, Sergei Rouvimov and Gregory L. Snider

J. Vac. Sci. Technol. A **34**, 01A122 (2016);  
<http://dx.doi.org/10.1116/1.4935960>

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---

S

## **Low-temperature sequential pulsed chemical vapor deposition of ternary B<sub>x</sub>Ga<sub>1-x</sub>N and B<sub>x</sub>In<sub>1-x</sub>N thin film alloys**

Ali Haider, Seda Kizir, Cagla Ozgit-Akgun, Ali Kemal Okyay and Necmi Biyikli

J. Vac. Sci. Technol. A **34**, 01A123 (2016);  
<http://dx.doi.org/10.1116/1.4936072>

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---

S

## **Microscratch testing method for systematic evaluation of the adhesion of atomic layer deposited thin films on silicon**

Lauri Kilpi, Oili M. E. Ylivaara, Antti Vaajoki, Jari Malm, Sakari Sintonen, Marko Tuominen, Riikka L. Puurunen and Helena Ronkainen

J. Vac. Sci. Technol. A **34**, 01A124 (2016);  
<http://dx.doi.org/10.1116/1.4935959>

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---

S

## **Substrate temperature influence on the properties of GaN thin films grown by hollow-cathode plasma-assisted atomic layer deposition**

Mustafa Alevli, Neşre Gungor, Ali Haider, Seda Kizir, Shahid A. Leghari and Necmi Biyikli

J. Vac. Sci. Technol. A **34**, 01A125 (2016);  
<http://dx.doi.org/10.1116/1.4936230>

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---

S

## **Ag films grown by remote plasma enhanced atomic layer deposition on different substrates**

Akinwumi A. Amusan, Bodo Kalkofen, Hassan Gargouri, Klaus Wandel, Cay Pinnow, Marco Lisker and Edmund P. Burte

J. Vac. Sci. Technol. A **34**, 01A126 (2016);  
<http://dx.doi.org/10.1116/1.4936221>

**+ VIEW DESCRIPTION**

---

S

## **Plasma-enhanced atomic layer deposition of titanium oxynitrides films: A comparative spectroscopic and electrical study**

Małgorzata Sowińska, Karsten Henkel, Dieter Schmeißer, Irina Kärkkäinen, Jessica Schneidewind, Franziska Naumann, Bernd Gruska and Hassan Gargouri

J. Vac. Sci. Technol. A **34**, 01A127 (2016);  
<http://dx.doi.org/10.1116/1.4936227>

**+ VIEW DESCRIPTION**

---

S

## **Atomic layer deposition of alternative glass microchannel plates**

Aileen O'Mahony, Christopher A. Craven, Michael J. Minot, Mark A. Popecki, Joseph M. Renaud, Daniel C. Bennis, Justin L. Bond, Michael E. Stochaj, Michael R. Foley, Bernhard W. Adams, Anil U. Mane, Jeffrey W. Elam, Camden Ertley and Oswald H. W. Siegmund

J. Vac. Sci. Technol. A **34**, 01A128 (2016);  
<http://dx.doi.org/10.1116/1.4936231>

**+ VIEW DESCRIPTION**



---

S **Comparison of tungsten films grown by CVD and hot-wire assisted atomic layer deposition in a cold-wall reactor**

Mengdi Yang, Antonius A. I. Aarnink, Alexey Y. Kovalgin, Dirk. J. Gravesteijn, Rob A. M. Wolters and Jurriaan Schmitz  
J. Vac. Sci. Technol. A **34**, 01A129 (2016);  
<http://dx.doi.org/10.1116/1.4936387>

**+ VIEW DESCRIPTION**

---

S **Luminescence properties of lanthanide and ytterbium lanthanide titanate thin films grown by atomic layer deposition**

Per-Anders Hansen, Helmer Fjellvåg, Terje G. Finstad and Ola Nilsen  
J. Vac. Sci. Technol. A **34**, 01A130 (2016);  
<http://dx.doi.org/10.1116/1.4936389>

**+ VIEW DESCRIPTION**

---

S **Novel chemoresistive CH<sub>4</sub> sensor with 10 ppm sensitivity based on multiwalled carbon nanotubes functionalized with SnO<sub>2</sub> nanocrystals**

Md Tanim Humayun, Ralu Divan, Yuzi Liu, Lara Gundel, Paul A. Solomon and Igor Paprotny  
J. Vac. Sci. Technol. A **34**, 01A131 (2016);  
<http://dx.doi.org/10.1116/1.4936384>

**+ VIEW DESCRIPTION**

---

## S **Atomic layer deposition of boron-containing films using B<sub>2</sub>F<sub>4</sub>**

Anil U. Mane, Jeffrey W. Elam, Alexander Goldberg, Thomas E. Seidel, Mathew D. Halls, Michael I. Current, Joseph Despres, Oleg Byl, Ying Tang and Joseph Sweeney

J. Vac. Sci. Technol. A **34**, 01A132 (2016);  
<http://dx.doi.org/10.1116/1.4935651>

**+ VIEW DESCRIPTION**

---

## S **Electrical characterization of atomic layer deposited Al<sub>2</sub>O<sub>3</sub>/InN interfaces**

Ye Jia, Amir M. Dabiran and Uttam Singiseti

J. Vac. Sci. Technol. A **34**, 01A133 (2016);  
<http://dx.doi.org/10.1116/1.4936928>

**+ VIEW DESCRIPTION**

---

## S **Rapid visible color change and physical swelling during water exposure in triethanolamine-metalcone films formed by molecular layer deposition**

Paul C. Lemaire, Christopher J. Oldham and Gregory N. Parsons

J. Vac. Sci. Technol. A **34**, 01A134 (2016);  
<http://dx.doi.org/10.1116/1.4937222>

**+ VIEW DESCRIPTION**

---

## S **Enhancing of catalytic properties of vanadia via surface doping with phosphorus using atomic layer deposition**

Verena E. Stempel, Daniel Löffler, Jutta Kröhnert, Katarzyna Skorupska, Benjamin Johnson, Raoul Naumann d'Alnoncourt, Matthias Driess and Frank Rosowski

J. Vac. Sci. Technol. A **34**, 01A135 (2016);  
<http://dx.doi.org/10.1116/1.4936390>

**+ VIEW DESCRIPTION**

---

S

## **Low-temperature SiON films deposited by plasma-enhanced atomic layer deposition method using activated silicon precursor**

Sungin Suh, Seung Wook Ryu, Seongjae Cho, Jun-Rae Kim, Seongkyung Kim, Cheol Seong Hwang and Hyeong Joon Kim

J. Vac. Sci. Technol. A **34**, 01A136 (2016);

<http://dx.doi.org/10.1116/1.4937734>

**+ VIEW DESCRIPTION**

---

S

## **Comparison of trimethylgallium and triethylgallium as “Ga” source materials for the growth of ultrathin GaN films on Si (100) substrates via hollow-cathode plasma-assisted atomic layer deposition**

Mustafa Alevli, Ali Haider, Seda Kizir, Shahid A. Leghari and Necmi Biyikli

J. Vac. Sci. Technol. A **34**, 01A137 (2016);

<http://dx.doi.org/10.1116/1.4937725>

**+ VIEW DESCRIPTION**

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OA

## **Atomic layer deposition by reaction of molecular oxygen with tetrakisdimethylamido-metal precursors**

J Provine, Peter Schindler, Jan Torgersen, Hyo Jin Kim, Hans-Peter Karnthaler and Fritz B. Prinz

J. Vac. Sci. Technol. A **34**, 01A138 (2016);

<http://dx.doi.org/10.1116/1.4937991>

**+ VIEW DESCRIPTION**

---

S

## **Atomic layer deposition of Al<sub>2</sub>O<sub>3</sub> for single electron transistors utilizing Pt oxidation and reduction**

Michael S. McConnell, Louisa C. Schneider, Golnaz Karbasian, Sergei Rouvimov, Alexei O. Orlov and Gregory L. Snider  
J. Vac. Sci. Technol. A **34**, 01A139 (2016);  
<http://dx.doi.org/10.1116/1.4937992>

**+ VIEW DESCRIPTION**

---

S

## **Plasma enhanced atomic layer deposition of silicon nitride using neopentasilane**

Stephen Weeks, Greg Nowling, Nobu Fuchigami, Michael Bowes and Karl Littau  
J. Vac. Sci. Technol. A **34**, 01A140 (2016);  
<http://dx.doi.org/10.1116/1.4937993>

**+ VIEW DESCRIPTION**

---

S

## **Ultraviolet photodetector based on Mg<sub>x</sub>Zn<sub>1-x</sub>O films using plasma-enhanced atomic layer deposition**

Yu-Chang Lin, Hsin-Ying Lee and Ching-Ting Lee  
J. Vac. Sci. Technol. A **34**, 01A141 (2016);  
<http://dx.doi.org/10.1116/1.4938074>

**+ VIEW DESCRIPTION**

---

S

## **Atomic layer deposition of NiS and its application as cathode material in dye sensitized solar cell**

Neha Mahuli and Shaibal K. Sarkar  
J. Vac. Sci. Technol. A **34**, 01A142 (2016);  
<http://dx.doi.org/10.1116/1.4938078>

**+ VIEW DESCRIPTION**

---

## S **Standing and sitting adlayers in atomic layer deposition of ZnO**

Zhengning Gao, Fei Wu, Yoon Myung, Ruixiang Fei, Ravindra Kanjolia, Li Yang and Parag Banerjee

J. Vac. Sci. Technol. A **34**, 01A143 (2016);

<http://dx.doi.org/10.1116/1.4938080>

[+ VIEW DESCRIPTION](#)

---

## S **Thickness-dependent growth orientation of F-doped ZnO films formed by atomic layer deposition**

Kyung-Mun Kang, Yong-June Choi, Geun Young Yeom and Hyung-Ho Park

J. Vac. Sci. Technol. A **34**, 01A144 (2016);

<http://dx.doi.org/10.1116/1.4938180>

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---

## S **Periodic oxidation for fabricating titanium oxynitride thin films via atomic layer deposition**

Shinya Iwashita, Shintaro Aoyama, Masayuki Nasu, Kouji Shimomura, Naotaka Noro, Toshio Hasegawa, Yasushi Akasaka and Kohei Miyashita

J. Vac. Sci. Technol. A **34**, 01A145 (2016);

<http://dx.doi.org/10.1116/1.4938106>

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---

## S **Spatial atomic layer deposition on flexible porous substrates: ZnO on anodic aluminum oxide films and Al<sub>2</sub>O<sub>3</sub> on Li ion battery electrodes**

Kashish Sharma, Dmitri Routkevitch, Natalia Varaksa and Steven M. George

J. Vac. Sci. Technol. A **34**, 01A146 (2016);

<http://dx.doi.org/10.1116/1.4937728>

[+ VIEW DESCRIPTION](#)

---

S

## **Low-temperature atomic layer deposition of TiO<sub>2</sub> thin layers for the processing of memristive devices**

Samuele Porro, Alladin Jasmin, Katarzyna Bejtka, Daniele Conti, Denis Perrone, Salvatore Guastella, Candido F. Pirri, Alessandro Chiolerio and Carlo Ricciardi

J. Vac. Sci. Technol. A **34**, 01A147 (2016);  
<http://dx.doi.org/10.1116/1.4938465>

**+ VIEW DESCRIPTION**

---

S

## **Inherent substrate-dependent growth initiation and selective-area atomic layer deposition of TiO<sub>2</sub> using “water-free” metal-halide/metal alkoxide reactants**

Sarah E. Atanasov, Berç Kalanyan and Gregory N. Parsons

J. Vac. Sci. Technol. A **34**, 01A148 (2016);  
<http://dx.doi.org/10.1116/1.4938481>

**+ VIEW DESCRIPTION**

---

S

## **Probabilistic distributions of pinhole defects in atomic layer deposited films on polymeric substrates**

Alexander S. Yersak and Yung-Cheng Lee

J. Vac. Sci. Technol. A **34**, 01A149 (2016);  
<http://dx.doi.org/10.1116/1.4938496>

**+ VIEW DESCRIPTION**

---

S

## **Simulation of nucleation and growth of atomic layer deposition phosphorus for doping of advanced FinFETs**

Thomas E. Seidel, Alexander Goldberg, Mat D. Halls and Michael I. Current

J. Vac. Sci. Technol. A **34**, 01A150 (2016);  
<http://dx.doi.org/10.1116/1.4938585>

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---

S **Properties of nanostructured undoped ZrO<sub>2</sub> thin film electrolytes by plasma enhanced atomic layer deposition for thin film solid oxide fuel cells**

Gu Young Cho, Seungtak Noh, Yoon Ho Lee, Sanghoon Ji, Soon Wook Hong, Bongjun Koo, Jihwan An, Young-Beom Kim and Suk Won Cha  
J. Vac. Sci. Technol. A **34**, 01A151 (2016);  
<http://dx.doi.org/10.1116/1.4938105>

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---

S **Low temperature platinum atomic layer deposition on nylon-6 for highly conductive and catalytic fiber mats**

J. Zachary Mundy, Arya Shafiefarhood, Fanxing Li, Saad A. Khan and Gregory N. Parsons  
J. Vac. Sci. Technol. A **34**, 01A152 (2016);  
<http://dx.doi.org/10.1116/1.4935448>

[+ VIEW DESCRIPTION](#)

TOP

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## ATOMIC LAYER ETCHING (ALE)

S **Fluorocarbon assisted atomic layer etching of SiO<sub>2</sub> and Si using cyclic Ar/C<sub>4</sub>F<sub>8</sub> and Ar/CHF<sub>3</sub> plasma**

Dominik Metzler, Chen Li, Sebastian Engelmann, Robert L. Bruce, Eric A. Joseph and Gottlieb S. Oehrlein  
J. Vac. Sci. Technol. A **34**, 01B101 (2016);  
<http://dx.doi.org/10.1116/1.4935462>

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---

## Application of cyclic fluorocarbon/argon discharges to device patterning

Dominik Metzler, Kishore Uppireddi, Robert L. Bruce, Hiroyuki Miyazoe, Yu Zhu, William Price, Ed S. Sikorski, Chen Li, Sebastian U. Engelmann, Eric A. Joseph and Gottlieb S. Oehrlein

J. Vac. Sci. Technol. A **34**, 01B102 (2016);

<http://dx.doi.org/10.1116/1.4935460>

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## Initial evaluation and comparison of plasma damage to atomic layer carbon materials using conventional and low $T_e$ plasma sources

Ashish V. Jagtiani, Hiroyuki Miyazoe, Josephine Chang, Damon B. Farmer, Michael Engel, Deborah Neumayer, Shu-Jen Han, Sebastian U. Engelmann, David R. Boris, Sandra C. Hernández, Evgeniya H. Lock, Scott G. Walton and Eric A. Joseph

J. Vac. Sci. Technol. A **34**, 01B103 (2016);

<http://dx.doi.org/10.1116/1.4936622>

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